International Rectifier

PD-91720 IRF1010ES IRF1010EL

- Advanced Process Technology
- Surface Mount (IRF1010ES)
- Low-profile through-hole (IRF1010EL)
- 175°C Operating Temperature
- Fast Switching
- Fully Avalanche Rated

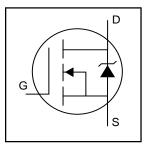
Description

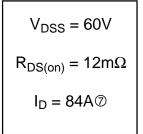
Advanced HEXFET® Power MOSFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

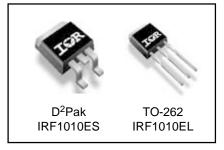
The D²Pak is a surface mount power package capable of accommodating die sizes up to HEX-4. It provides the highest power capability and the lowest possible onresistance in any existing surface mount package. The D²Pak is suitable for high current applications because of its low internal connection resistance and can dissipate up to 2.0W in a typical surface mount application.

The through-hole version (IRF1010EL) is available for low-profile applications.

HEXFET® Power MOSFET







Absolute Maximum Ratings

	Parameter	Max.	Units
$I_D @ T_C = 25^{\circ}C$	Continuous Drain Current, V _{GS} @ 10V	84⑦	
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V	59	Α
I _{DM}	Pulsed Drain Current ①	330	
P _D @T _C = 25°C	Power Dissipation	200	W
	Linear Derating Factor	1.4	W/°C
V_{GS}	Gate-to-Source Voltage	± 20	V
I _{AR}	Avalanche Current①	50	Α
E _{AR}	Repetitive Avalanche Energy①	17	mJ
dv/dt	Peak Diode Recovery dv/dt ③	4.0	V/ns
T _J	Operating Junction and	-55 to + 175	
T _{STG}	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)	
	Mounting torque, 6-32 or M3 srew	10 lbf•in (1.1N•m)	

Thermal Resistance

	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case		0.75	°C/W
$R_{\theta JA}$	Junction-to-Ambient (PCB mount)**		40	0, **

Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
V _{(BR)DSS}	Drain-to-Source Breakdown Voltage	60			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		0.064		V/°C	Reference to 25°C, I _D = 1mA
R _{DS(on)}	Static Drain-to-Source On-Resistance			12	mΩ	V _{GS} = 10V, I _D = 50A ④
V _{GS(th)}	Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$
g _{fs}	Forward Transconductance	69			S	V _{DS} = 25V, I _D = 50A⊕
I _{DSS}	Drain-to-Source Leakage Current			25	μA	$V_{DS} = 60V$, $V_{GS} = 0V$
צפטי	Brain to Gource Leakage Guiterit			250	μΛ	$V_{DS} = 48V, V_{GS} = 0V, T_{J} = 150^{\circ}C$
1	Gate-to-Source Forward Leakage			100	nA	V _{GS} = 20V
I _{GSS}	Gate-to-Source Reverse Leakage			-100	l IIA	V _{GS} = -20V
Qg	Total Gate Charge			130		I _D = 50A
Q _{gs}	Gate-to-Source Charge			28	nC	$V_{DS} = 48V$
Q_{gd}	Gate-to-Drain ("Miller") Charge			44		V_{GS} = 10V, See Fig. 6 and 13
t _{d(on)}	Turn-On Delay Time		12			V _{DD} = 30V
t _r	Rise Time		78		ns	$I_D = 50A$
t _{d(off)}	Turn-Off Delay Time		48		115	$R_G = 3.6\Omega$
t _f	Fall Time		53			V _{GS} = 10V, See Fig. 10 ⊕
	Internal Drain Inductance		4.5			Between lead,
L _D	Internal Drain Inductance				nH	6mm (0.25in.)
L _S	Internal Source Inductance		7.5		110	from package
						and center of die contact
C _{iss}	Input Capacitance		3210			V _{GS} = 0V
C _{oss}	Output Capacitance		690			$V_{DS} = 25V$
C _{rss}	Reverse Transfer Capacitance		140		pF	f = 1.0MHz, See Fig. 5
E _{AS}	Single Pulse Avalanche Energy2		1180©	320⑥	mJ	I _{AS} = 50A, L = 260μH

Source-Drain Ratings and Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions								
Is	Continuous Source Current			0.4.0		MOSFET symbol								
	(Body Diode)	8	84⑦	A	showing the									
I _{SM}	Pulsed Source Current		33				20		220	220	220	220	, ,	integral reverse
	(Body Diode)①			330		p-n junction diode.								
V _{SD}	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C$, $I_S = 50A$, $V_{GS} = 0V$ ④								
t _{rr}	Reverse Recovery Time		73	110	ns	$T_J = 25$ °C, $I_F = 50$ A								
Q _{rr}	Reverse Recovery Charge		220	330	nC	di/dt = 100A/µs ④								
t _{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L _S +L _D)												

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)
- ② Starting $T_J = 25^{\circ}C$, $L = 260\mu H$ $R_G = 25\Omega$, $I_{AS} = 50A$, $V_{GS} = 10V$ (See Figure 12)
- $\begin{tabular}{ll} \begin{tabular}{ll} \be$
- 4 Pulse width \leq 400 μ s; duty cycle \leq 2%.
- ⑤ This is a typical value at device destruction and represents operation outside rated limits.
- $\mbox{\em 6}$ This is a calculated value limited to T_J = 175 $\mbox{\em c}$.
- ② Calculated continuous current based on maximum allowable junction temperature. Package limitation current is 75A.
- **When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994

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IRF1010ES/IRF1010EL

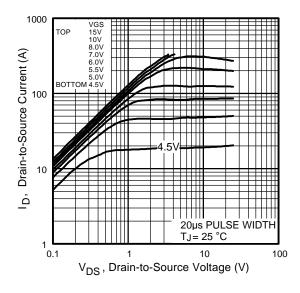


Fig 1. Typical Output Characteristics

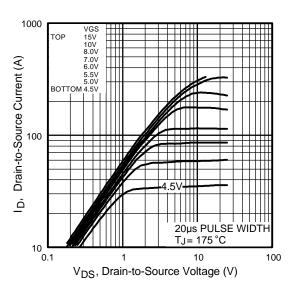


Fig 2. Typical Output Characteristics

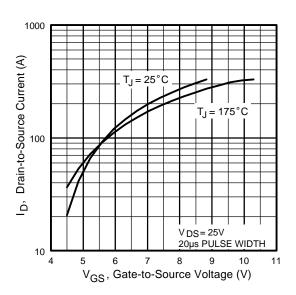


Fig 3. Typical Transfer Characteristics

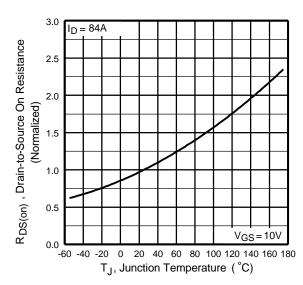


Fig 4. Normalized On-Resistance Vs. Temperature

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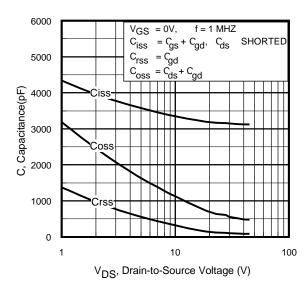


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

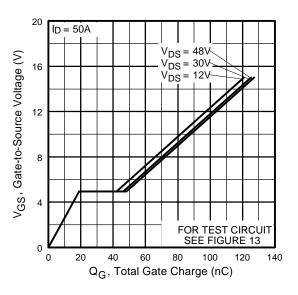


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

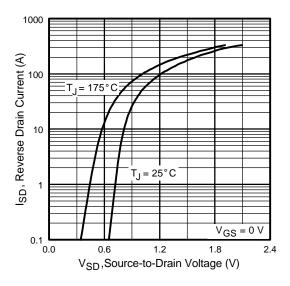


Fig 7. Typical Source-Drain Diode Forward Voltage

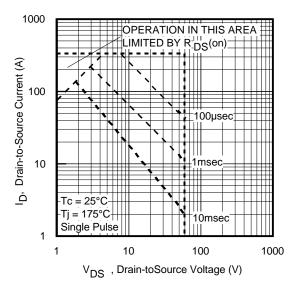


Fig 8. Maximum Safe Operating Area

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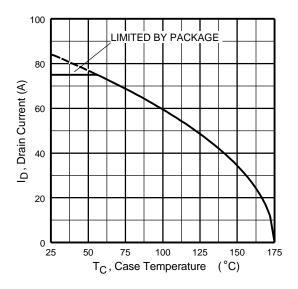


Fig 9. Maximum Drain Current Vs. Case Temperature

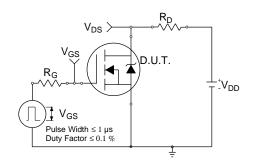


Fig 10a. Switching Time Test Circuit

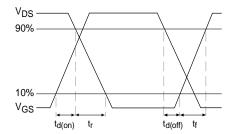


Fig 10b. Switching Time Waveforms

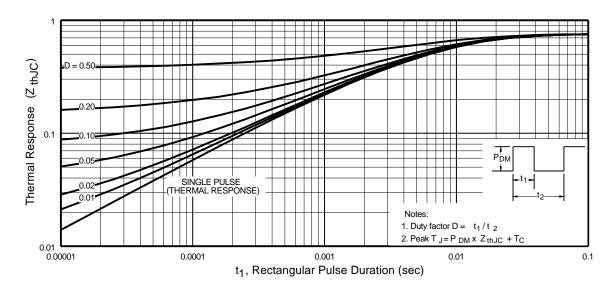


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

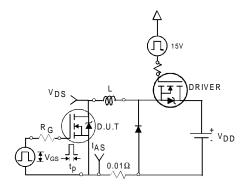


Fig 12a. Unclamped Inductive Test Circuit

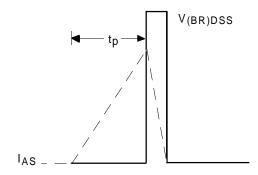


Fig 12b. Unclamped Inductive Waveforms

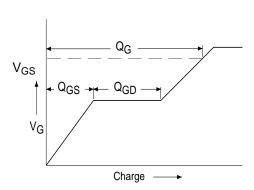


Fig 13a. Basic Gate Charge Waveform

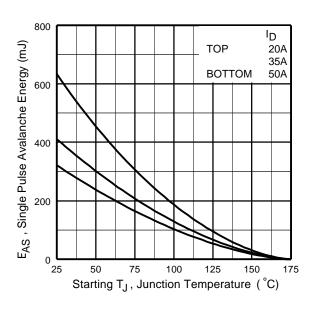


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

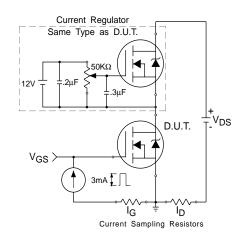
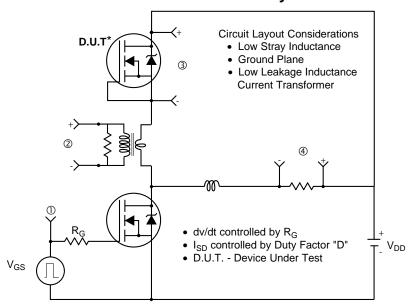
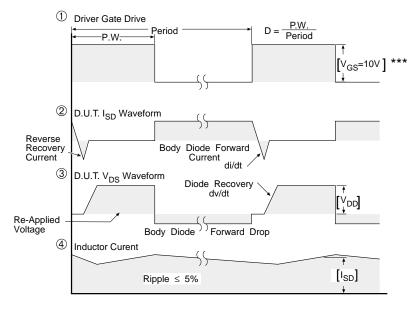


Fig 13b. Gate Charge Test Circuit

Peak Diode Recovery dv/dt Test Circuit



* Reverse Polarity of D.U.T for P-Channel



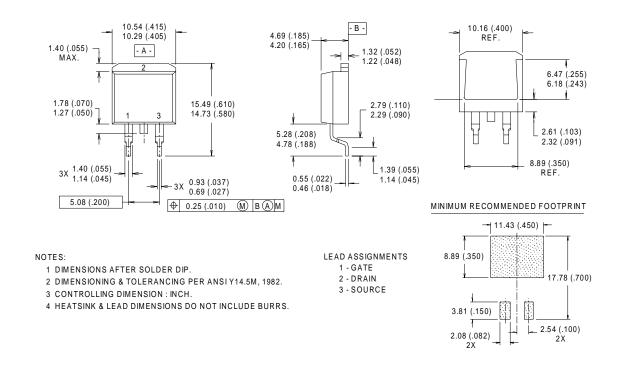
^{***} V_{GS} = 5.0V for Logic Level and 3V Drive Devices

Fig 14. For N-channel HEXFET® power MOSFETs

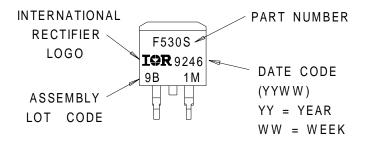
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D²Pak Package Outline



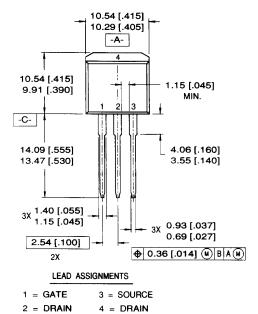
D²Pak Part Marking Information

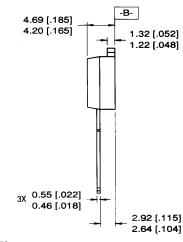


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IRF1010ES/IRF1010EL

TO-262 Package Outline





NOTES:

- 1. DIMENSIONING & TOLERANCING PER ANSI Y14.5M-1982
- 2. CONTROLLING DIMENSION: INCH.
- 3. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].
- 4. HEATSINK & LEAD DIMENSIONS DO NOT INCLUDE BURRS.

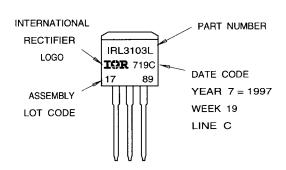
TO-262 Part Marking Information

EXAMPLE: THIS IS AN IRL3103L

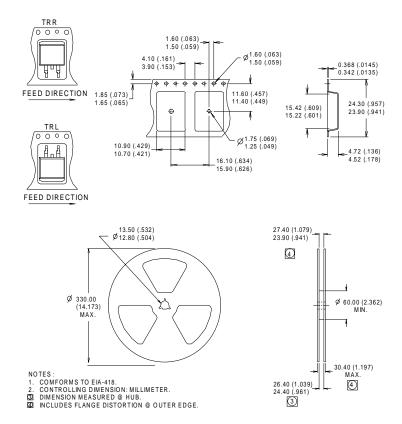
LOT CODE 1789

ASSEMBLED ON WW 19, 1997

IN THE ASSEMBLY LINE "C"



D²Pak Tape & Reel Information



Data and specifications subject to change without notice. This product has been designed and qualified for the industrial market.

Qualification Standards can be found on IR's Web site.



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TAC Fax: (310) 252-7903

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